Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/766,874	YAMASHITA ET AL.	
Examiner	Art Unit	
Christopher RoDee	1756	

SEARCHED				
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Search updated	8/18/2006	CDR		